FORM PTO-1449 (MODIFIED)	ATTY. DOCKET NO. 36856.617	SERIAL NO.: Currently unknown
LIST OF PATENTS AND PUBLICATIONS FOR APPLICANTS INFORMATION DISCLOSURE STATEMENT (USE SEVERAL SHEETS IF NECESSARY)	APPLICANT(S): Eiichi TAKATA e	t al. 54921
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Initial	Document Number	Date	Name	Class	appropriate
De	AA 5,906,950	05/1999	Keller et al.	438	1)/3
-r	AB 5,932,950	08/1999	Yamada et al.	310	2/13
	AC 6,185,801	02/2001	Kadota et al.	29	25.35
	AD 5,497,726	03/1996	Shikata et al.	110	89
f	AE 5,446,329	08/1995	Nakahata et al.	310	3/3
- d	AF 5,356,870	10/1994	Fujiwara et al.	705	329
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Del.	AG 2-189011 (With Abstracts)	07/1990	Japan		
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	AJ 6-188664 (With Abstracts)	07/1994	Japan		
	AK 6-120759 (With Abstracts)	04/1994	Japan		
,	AL 6-120416 (With Abstracts)	04/1994	Japan		
٦	AM 6-97760 (With Abstracts)	04/1994	Japan		
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pe,	AP R. SUBRAMANIAN et al., "Proc SAW Characteristics; 01/1996; IEEE	luction Trimn	ning of SAW Devices Using CF ₄ Ch		Effects on
Be	AR Takehiko UNO et al; "Frequency Communications Laboratories, Musas	Trimming of	f SAW Devices by Sputter Etching";	NTT Electrica	l
<i>p</i> ,	Electronics, Tokyo 1985; Japanese Jon	urnal of Appli	ed Phusics; Vol. 25 (1986) Supplement	ent 25-1; PP. 1	45-147
		 			
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	AB 5,914,646	06/1999	Hashimoto	333	1,95
	AC 4,756,794	07/1988	Yoder	156	1/1/2
	AD 5,235,236	08/1993	Nakahata et al.	310	313
	AE 5,774,962	07/1998	Satoh et al.	29	312
<u> </u>	AF 4,403,165	09/1983	Ballato et al.		313
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FORM PTO-1449 (MODIFIED)	ATTY. DOCKET NO. 36856.617	SERIAL NO.: 10/054,921
LIST OF PATENTS AND PUBLICATIONS FOR APPLICANTS INFORMATION DISCLOSURE STATEMENT (USE SEVERAL SHEETS IF NECESSARY)	APPLICANT(S): Eiichi TAKATA COPY OF PA ORIGINALLY	et al. PERS FILED AUG 2 0 2002
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FORM PTO-1449 (MODIFIED) TRADEMAR	ATTY. DOCKET NO. 36856.617	SERIAL NO. : 10/054,921
LIST OF PATENTS AND PUBLICATIONS FOR APPLICANTS INFORMATION DISCLOSURE STATEMENT	APPLICANT(S): Eiichi TAKATA e	et al. PECHNOLOGY CELL FORDS
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